

**Notice of References Cited**

Application/Control No.

10/621,418

Applicant(s)/Patent Under  
Reexamination  
ONNO ET AL.

Examiner

Fikremariam Yalew

Art Unit

2436

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0027994	03-2002	Katayama et al.	380/269
*	B	US-7,184,548	02-2007	Wee et al.	380/37
*	C	US-4,685,098	08-1987	Yoshida, Tadao	369/59.18
*	D	US-7,003,666	02-2006	Inoue et al.	713/176
*	E	US-6,501,860	12-2002	Charrier et al.	382/240
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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	V				
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	X				

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